

Fabrication optimization of the photo-response characteristics of MoS₂ photodetectors for biosensing applications

Seungjun Ki, Byunghoon Ryu*, Younggeun Park, Katsuo Kurabayashi,
and Xiaogan Liang**

Mechanical Engineering Department, University of Michigan, Ann Arbor, MI 48109

* Argonne National Laboratory, Lemont, IL 60439

A therapeutic strategy guided by biomarkers, including cytokines and sepsis, has gained lots of attention because it can provide useful clinical information to determine immune status, disease presence, and progression.[1-2] Metallic nanoparticle-based localized surface plasmon resonance (LSRP) biosensors have been widely studied, seeking to achieve such immunological needs. In these biosensing devices, photodetectors with high responsivity and low internal noise levels need to be integrated to detect the subtle optical signals associated with biomarker binding events and therefore realize rapid, low-noise, and label-free detection capability as well as compatibility with point-of-care (PoC) setups. Recently, layered semiconductors (e.g., MoS₂ and WSe₂) have been emerging as strong candidate materials for this mission because of their outstanding photo-response characteristics. However, their practical implementation demands a systematical nanofabrication-oriented study to quantify and optimize the optoelectronic properties of MoS₂ photodetectors dedicated to biosensing applications.

In this work, we study the photo-response properties (e.g., photoresponsivity and noise equivalent power (NEP)) of in-plane MoS₂ photodetectors as the function of their geometric dimensions (e.g., thickness, length, and width of photoactive layers) and fabrication conditions (e.g., doping, etching, and substrate choice). This work enables the routine optimization for the photo-response characteristics of MoS₂-based biosensors, which are critical to optoelectronic biosensing applications.

Fig. 1 (a) shows the photo responsivity data measured from a set of MoS₂ photodetectors, plotted as the function of their MoS₂ photoactive layer thickness values. This result indicates that 7-20 nm thick MoS₂ photoactive layers results in relatively higher and constant photoresponsivity values. The MoS₂ thicknesses > 20 nm lead to a gradual decrease of photoresponsivity. This is attributed to the limited penetration depth of visible lights, resulting in a poor efficiency for collecting photo-generated carriers. When MoS₂ thickness < 7 nm, the photoresponsivity values are also relatively poor. This is attributed to the effects of dangling bonds or traps at MoS₂/SiO₂ interfaces. The thinner MoS₂ thickness is expected to result in a larger fraction of the photo-generated carriers, which can be attributed to the scattering effect by the dangling bonds or inter-layer defects on the SiO₂ substrate.[3] **Fig. 1 (b)** displays the low-frequency NEP spectra measured from the same set of MoS₂ photodetectors as well as a commercial CdS photodetector. For the optoelectronic biosensors, NEP plays an important role in determining the detection limits. Our devices exhibit a typical 1/f noise characteristic, which is attributed to MoS₂/SiO₂ inter-layer interfaces and charge impurities. Here, the NEP values at 1Hz are specifically chosen to further explore MoS₂-thickness-dependent noise characteristics because biomarker binding reaction events take place in a time scale of several seconds. **Fig. 1 (c)** exhibits that the devices with MoS₂ thickness in the range of 7-25 nm have the lowest NEP values, which are anticipated to lead to smaller detection limits for the optoelectronic biosensors. Figs. 1 (b) and (c) also indicate that the NEP values of all MoS₂ photodetectors are significantly lower than those measured from the

commercial CdS photodetector. This strongly implies that MoS₂ is advantageous for making photodetectors dedicated to optoelectronic biosensing applications.

This work provides a guideline for making 2D-material-based photo-response devices implemented for optoelectronic biosensing systems.

[1] Park, Y., Ryu, B., Deng, Q., Pan, B., Song, Y., Tian, Y., Alam, H.B., Li, Y., Liang, X. and Kurabayashi, K., *Small*, **16**, p.1905611 (2020).

[2] Park, Y., Ryu, B., Oh, B.R., Song, Y., Liang, X. and Kurabayashi, K., *Acs Nano*, **11**(6), pp.5697-5705 (2017).

[3] Scheuschner, N., Ochedowski, O., Kaulitz, A.M., Gillen, R., Schleberger, M. and Maultzsch, J., *Physical Review B*, **89**(12), p.125406 (2014).

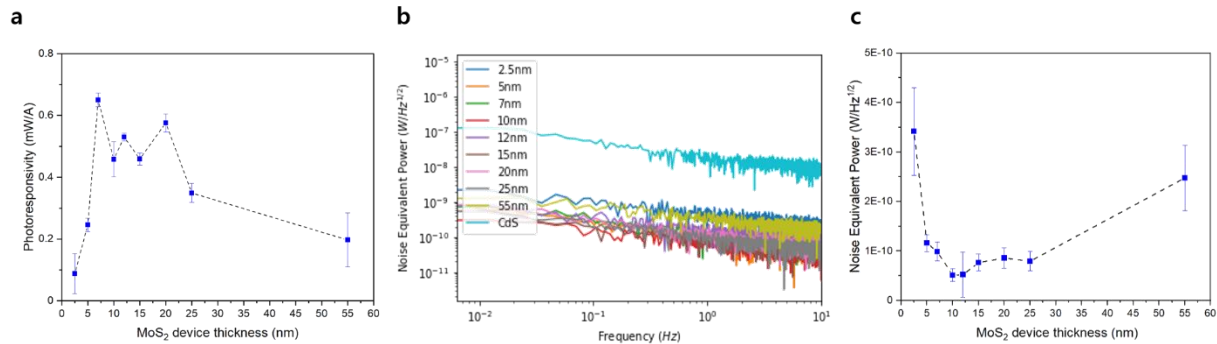


Fig. 1 Photo-response characteristics of the MoS₂ photodetectors with different MoS₂ thicknesses: (a) Photo responsivity as a function of MoS₂ photoactive thickness measured at $V_{ds} = 0.4V$ under light illumination at $\lambda = 450$ nm and $P = 0.43$ mW. (b) Noise equivalent power (NEP) spectra measured from MoS₂ devices with different thicknesses as well as a commercial CdS photodetector for comparison. (c) NEP values captured at 1 Hz plotted as the function of MoS₂ thicknesses.